

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/751,734	OCHIAI, KIYOE	
Examiner	Art Unit	-
Elias B. Hiruy	2837	

	SEAR	SEARCHED		
Class	Subclass	Date	Examiner	
318	34	9/21/2005	EH	
318	112	9/21/2005	EH	
318	. 41	10/5/2005	ЕН	
	*			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	J		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted on updated search findings and applicants amendment with SPE David Martin.	9/30/2005	EH		
Requested fast and focused search from STIC	9/30/2005	EH		
Searched US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT;IBM_TDB	9/21/2005	Ен		
	•			
•				
·	· ·			